Notice of References Cited Application/Control No. 10/632,082 Examiner Jason M Han Applicant(s)/Patent Under Reexamination LEE ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,114,372	05-1992	Fuchs, Herbert K.	445/3
-	В	US-5,138,528	08-1992	Altman et al.	361/760
	С	US-5,349,508	09-1994	Karbaf, Adam A.	362/217
	D	US-5,720,546	02-1998	Correll et al.	، 362/221
	Ε	US-5,907,218	05-1999	Altman et al.	315/56
	F	US-5,908,235	06-1999	Petrozello et al.	362/260
	G	US-6,050,704	04-2000	Park, Eui-yeul	362/260
	Н	US-6,079,851	06-2000	Altman et al.	362/260
	ı	US-6,217,190	04-2001	Altman et al.	362/221
	J	US-6,218,782	04-2001	Mallalieu, John	315/56
	К	US-6,459,203	10-2002	Kim, Kyoung Sub	315/56
	٦	US-2002/0149713	10-2002	Ishida et al.	349/58
	М	US-6,667,780	12-2003	Cho, Chun-Hyun	349/58

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					_
	Р					
	Q					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
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	w							
	x							

A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.